

**Search Notes (continued)**

Application/Control No.

10/734,905

Examiner

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Applicant(s)/Patent under  
Reexamination

HWANG ET AL.

Art Unit

2825

**SEARCHED**

Class	Subclass	Date	Examiner
716	2	8/10/2006	JSL
716	16	8/10/2006	JSL
716	17	8/10/2006	JSL
716	18	8/10/2006	JSL

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
716	2	8/10/2006	JSL
716	18	8/10/2006	JSL

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST [USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB]	8/10/2006	JSL
IEEE	8/10/2006	JSL
GOOGLE	8/10/2006	JSL